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Power Based Side-Channel Attack Analysis on PQC Algorithms

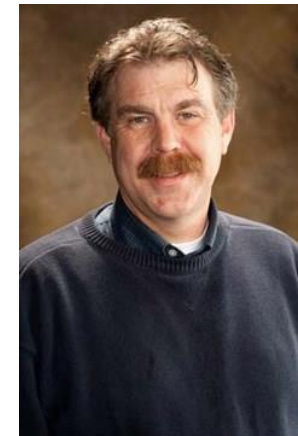
Tendayi Kamucheka, Michael Fahr, Tristen Teague, Alexander Nelson,
David Andrews, Miaoqing Huang

Acknowledgement: NIST – Award 60NANB20D016

The logo for the National Institute of Standards and Technology (NIST), consisting of the letters 'NIST' in a bold, black, sans-serif font.

About Us

- Computer Systems Design Lab & AESIR Lab at University of Arkansas – Computer Science & Computer Engineering Department
- Background – Hardware design, Embedded Systems, High Performance Computing, FPGAs, GPGPU



(Top) Tendayi Kamucheka, Michael Fahr, Tristen Teague

(Bottom) Alexander Nelson, David Andrews, Miaoqing Huang



Research Motivation

- Round 3 places significant interest on:
 - perfect forward secrecy,
 - **side-channel** and multi-key attacks,
 - and resistance to misuse.
- What can a well-equipped bad actor do with different types of equipment?

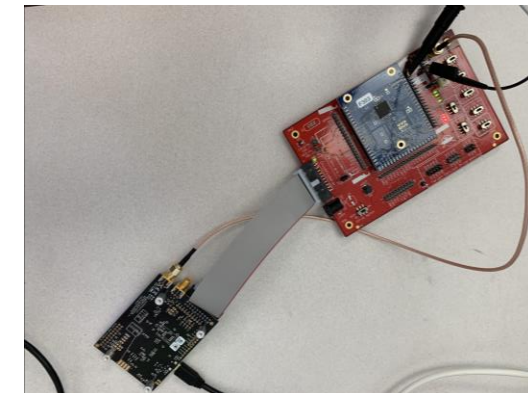


ARE WE SAFE FROM SIDE CHANNEL ATTACKS?



Our Approach: Implementation

- We setup a multi-platform testing lab for power analysis on round 3 PQC algorithms
- Equipment:
 - Tektronix MDO 3 Series oscilloscope
 - ChipWhisperer-Lite
- Current target platforms:
 - Xilinx Artix-7 FPGA
 - Xilinx Virtex-7 FPGA
 - Cortex M4 microcontroller
- Current implementations:
 - Hardware version of Kyber512 (Virtex-7 FPGA)
 - Software version of masked Kyber (Cortex-M4)
 - Using PQM4 library for other testing on Cortex-M4



Images:

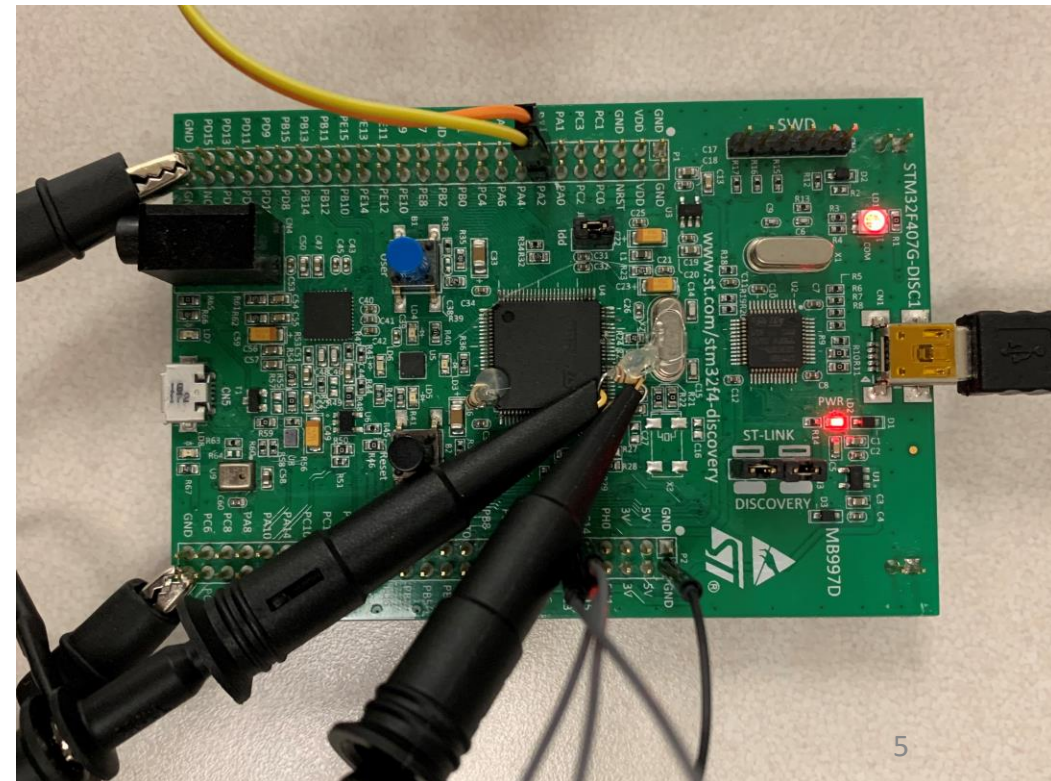
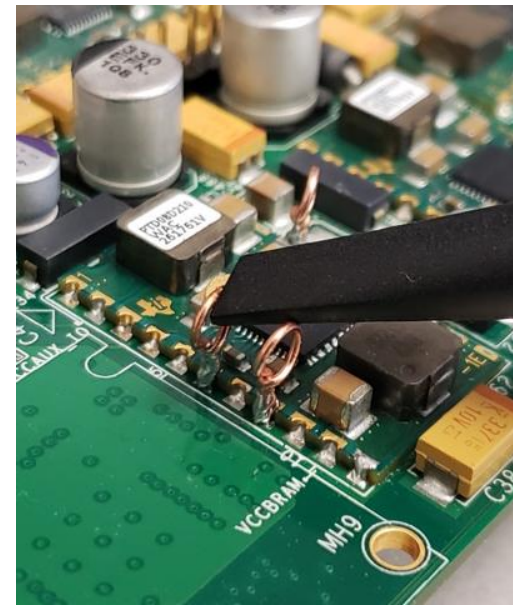
(top) Tektronix MDO 3-series oscilloscope <https://www.valuetronics.com/product/mdo34-3-bw-100-tektronix-mixed-domain-oscilloscope-new>

(bottom) ChipWhisperer-Lite (black) + UFO target board (red), Cortex-M4 (blue) board mounted on UFO target board.



Our Approach: Methodology

- Non-specific TVLA is used to validate our set up and identify potential leakage
- Experiment setup:
 - Control experiments – fixed vs. fixed inputs
 - Other experiments – fixed vs. random inputs
 - 2000 power traces per dataset
- FPGA board is modified to add probe points to measure current
- On microcontroller, traces are collected from current measured across a shunt resistor



Test Vector Leakage Assessment (TVLA)

- Welch's t-test, is statistical test that highlights differences between two datasets
- Outcome is pass or fail for each trace point
- A measure of 4.5 standard deviations is set as leakage threshold
 - 99.9999% confidence that anything above the threshold is due to leakage

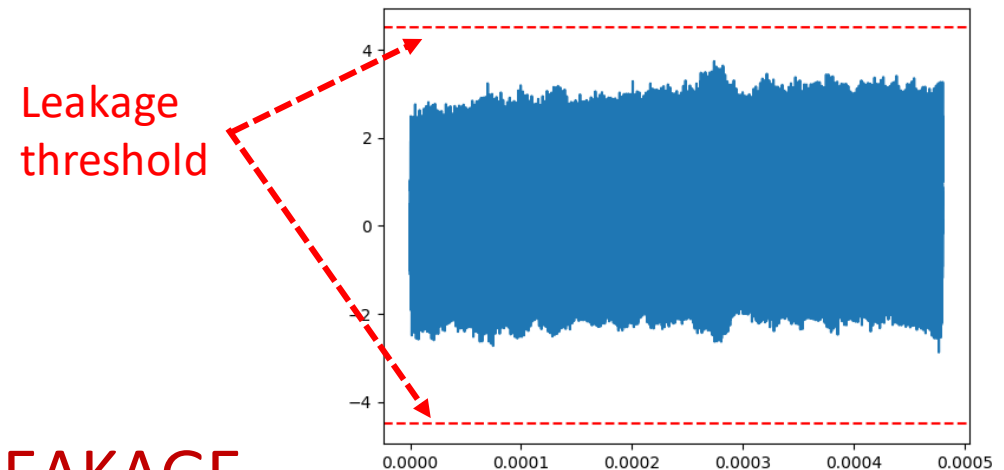
$$t = \frac{X_A - X_B}{\sqrt{\frac{S_A^2}{N_A} + \frac{S_B^2}{N_B}}}$$

Where:

X_A = sample mean for each point across time

S_A = standard deviation

N_A = cardinality

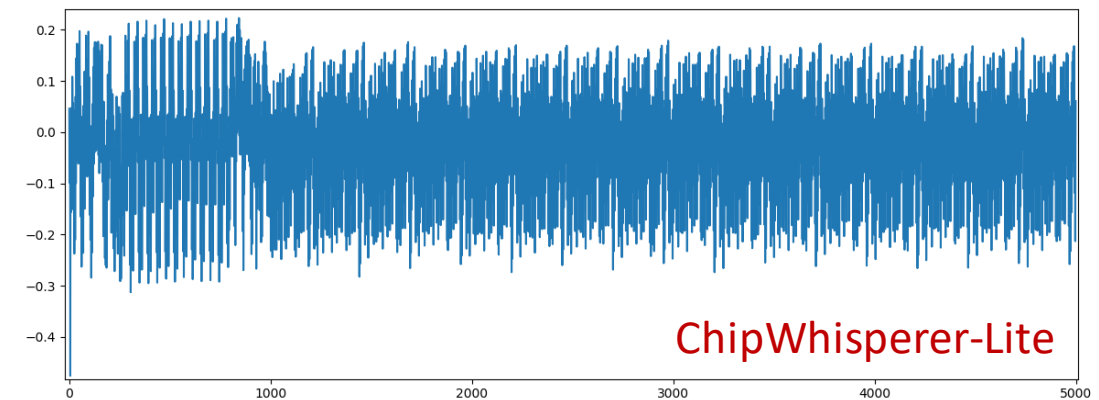
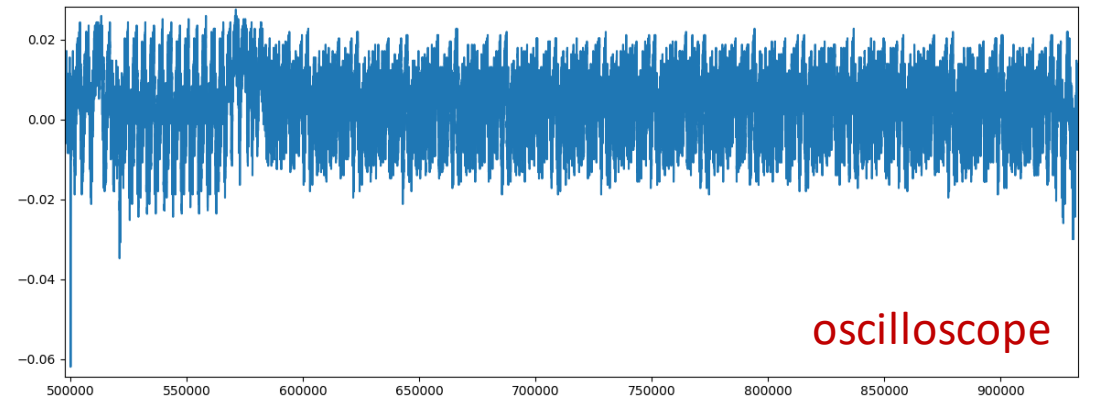


A TEST FOR SENSITIVE DATA-RELATED LEAKAGE



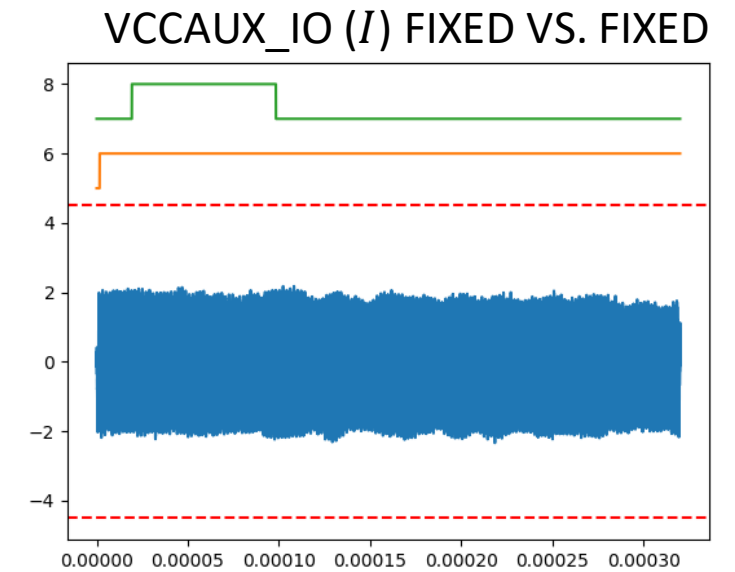
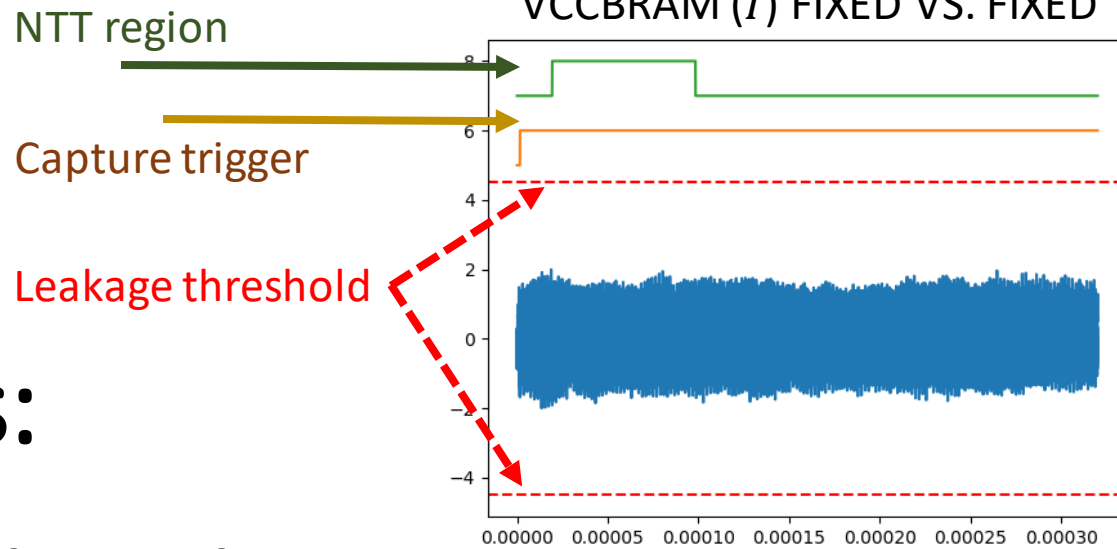
Results:

- Result of measuring voltage drop across shunt resistor
- Oscilloscope captures 1 million data points
- ChipWhisperer-Lite captures 5 thousand data points for same test



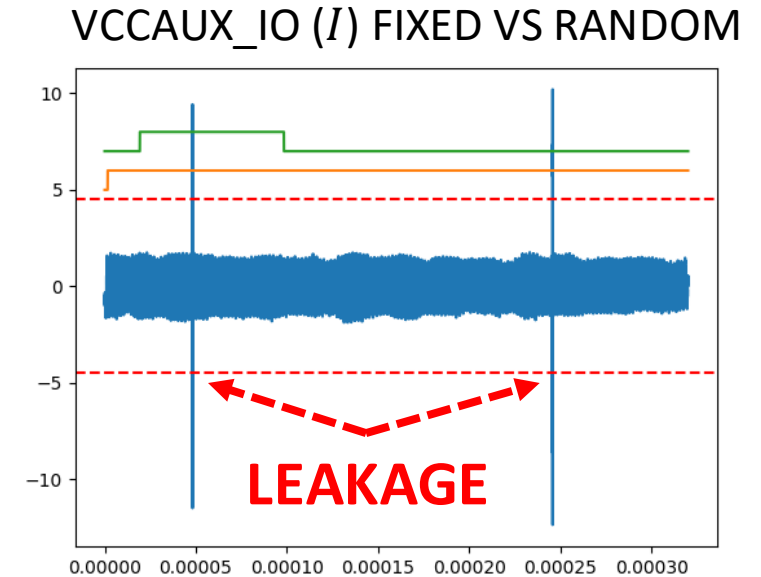
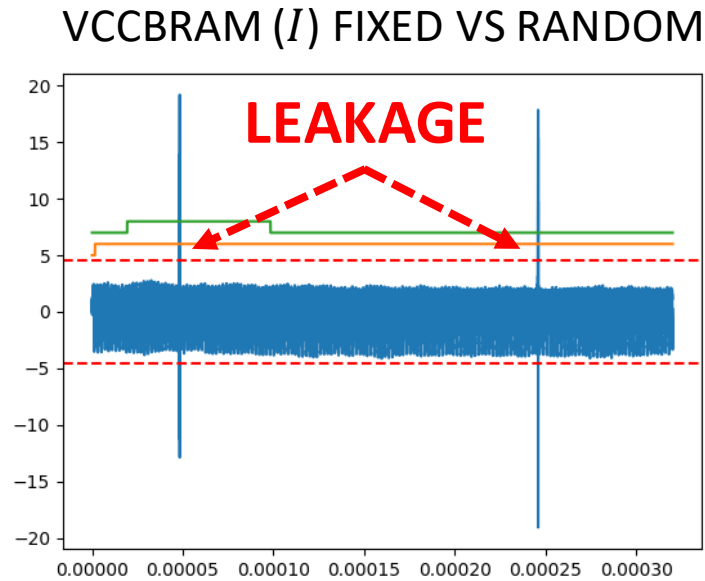
Oscilloscope captures at higher resolution





Results:

- Results of TVLA for current (I) measured on FPGA VCCBRAM and VCCAUX_IO
- Trace reveals two distinct leakage points



LEAKAGE TEST FAILS AT SAME POINTS IN BOTH TESTS



Conclusions

- We set up a multi-platform testing lab for power analysis side channel analysis
- We evaluate our setup with non-specific Test Vector Leakage Assessment
- Experiments show some leakage – Further analysis is required.
- Future work:
 - Further analysis of observed leakage
 - Exploiting leakage to develop side-channel assisted attacks



Questions?

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Thank You

